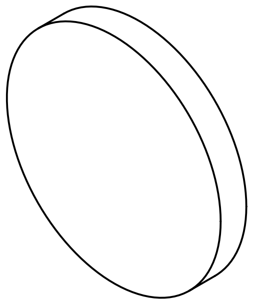
NOTES:

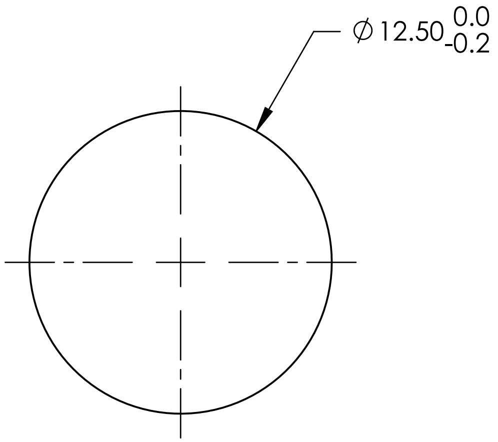
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 408 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 390nm @ 0° AOI
   T(abs): =50% FOR 400±4nm @ 0° AOI

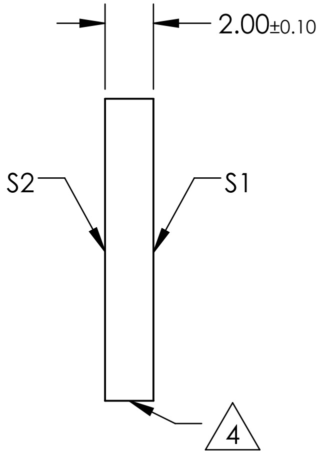
   S2:SINGLE LAYER MgF2

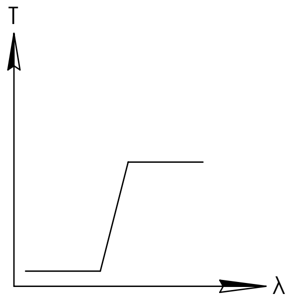
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 400nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN mm

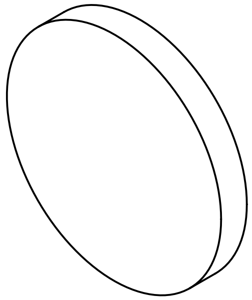
DWG NO 62974

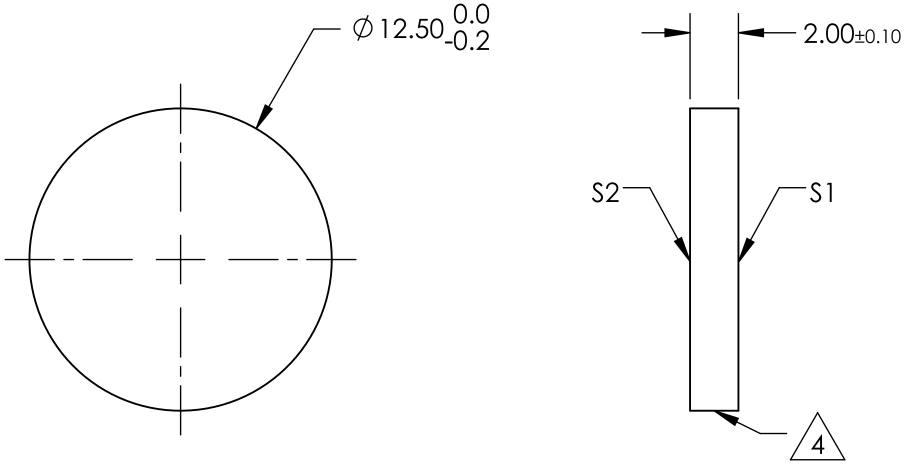
SHEET 1 OF 1

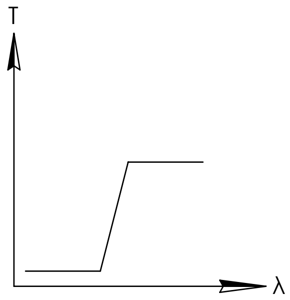
NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    - S1: HARD DIELECTRIC SPUTTERED
        - T(avg): ≥91% FROM 458 - 1650nm @ 0° AOI
        - T(avg): ≤0.01% FROM 200 - 440nm @ 0° AOI
        - T(abs): =50% FOR 450±4.5nm @ 0° AOI
    - S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING







LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 450nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	62975
SHEET	1 OF 1		

NOTES:

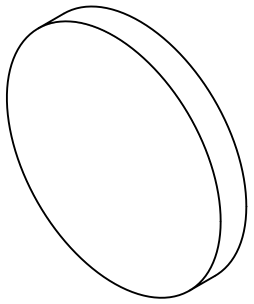
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 508 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 490nm @ 0° AOI
   T(abs): =50% FOR 500±5nm @ 0° AOI

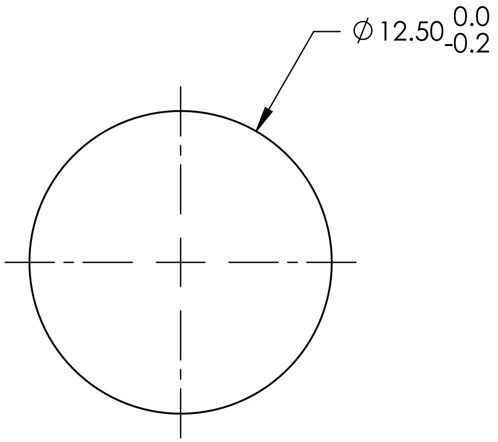
   S2:SINGLE LAYER MgF2

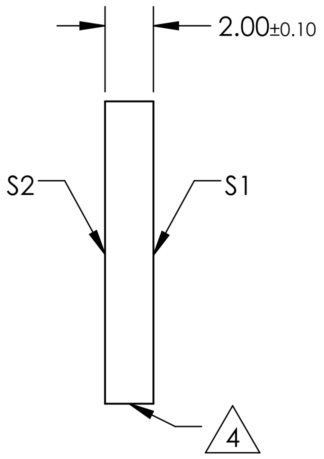
△4. FINE GRIND SURFACE

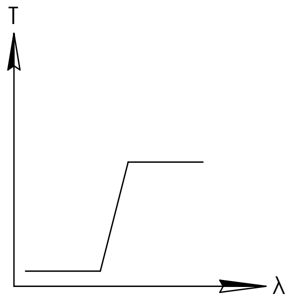
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 500nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN: mm

DWG NO: 62976

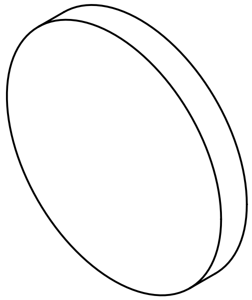
SHEET 1 OF 1

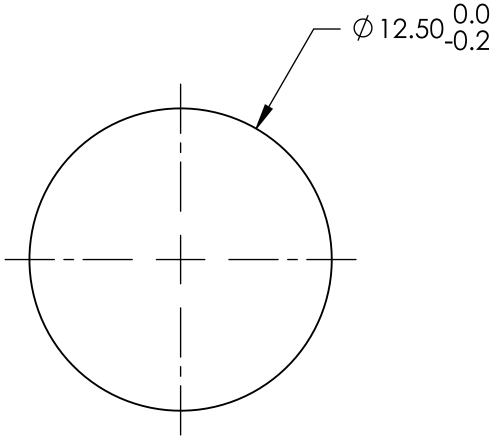
NOTES:

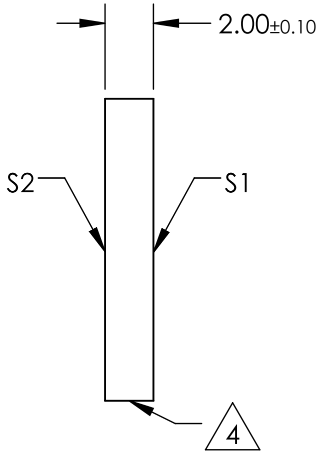
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 560 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 539nm @ 0° AOI
   T(abs): =50% FOR 550±5.5nm @ 0° AOI

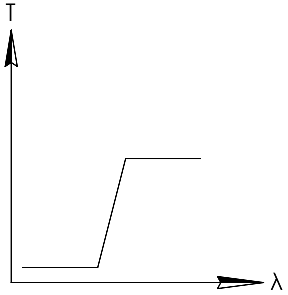
   S2:SINGLE LAYER MgF2
4. △ FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 550nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN: mm

DWG NO: 62977

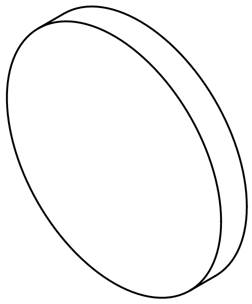
SHEET 1 OF 1

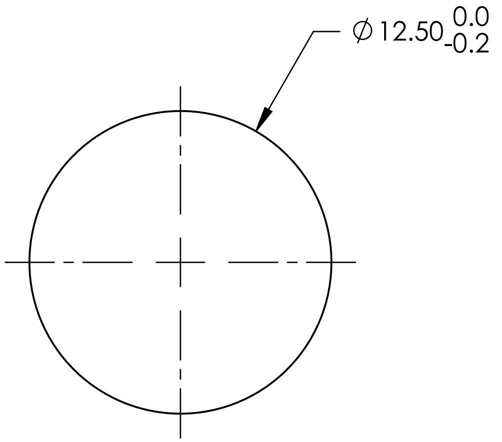
NOTES:

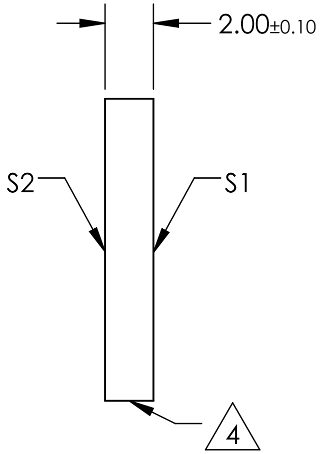
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 610 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 588nm @ 0° AOI
   T(abs): =50% FOR 600±6nm @ 0° AOI

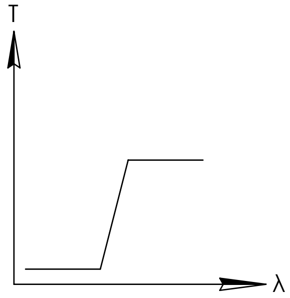
   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY: DO NOT MANUFACTURE PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 600nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	62978

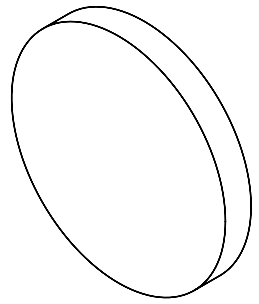
SHEET 1 OF 1

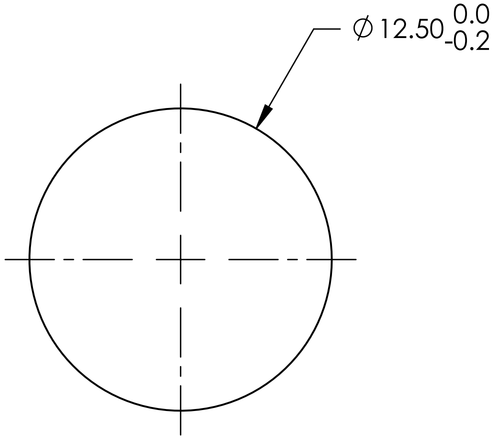
NOTES:

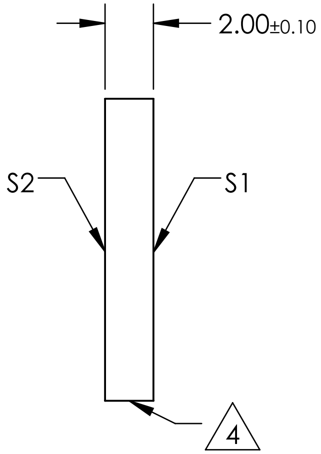
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 660 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 637nm @ 0° AOI
        T(abs): =50% FOR 650±6.5nm @ 0° AOI

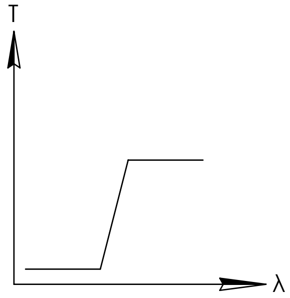
    S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

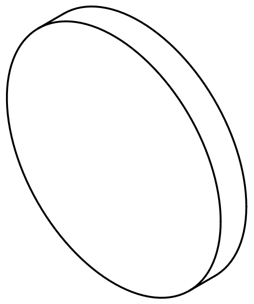
THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 650nm, HIGH PERFORMANCE LONGPASS FILTER		
ALL DIMS IN	mm	DWG NO	62979	SHEET 1 OF 1	

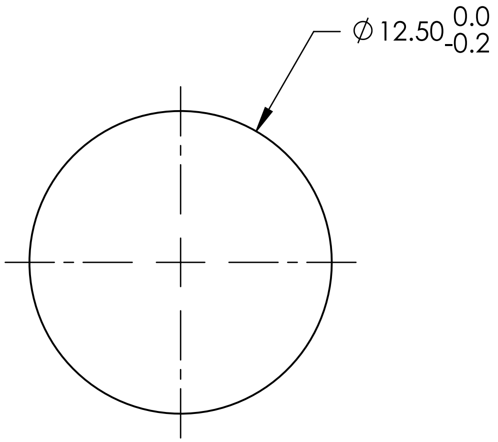
NOTES:

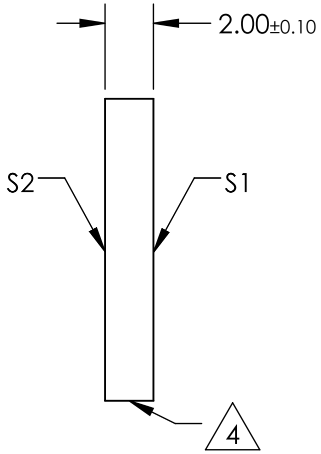
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 765 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 735nm @ 0° AOI
   T(abs): =50% FOR 750±7.5nm @ 0° AOI

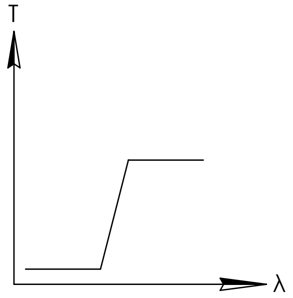
   S2:SINGLE LAYER MgF2
4. △ FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

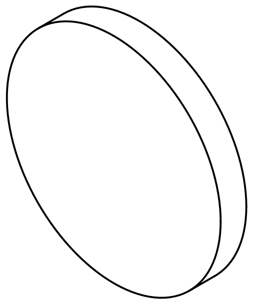
TITLE	Ø12.5mm, 750nm, HIGH PERFORMANCE LONGPASS FILTER		
ALL DIMS IN mm	DWG NO	66226	SHEET 1 OF 1

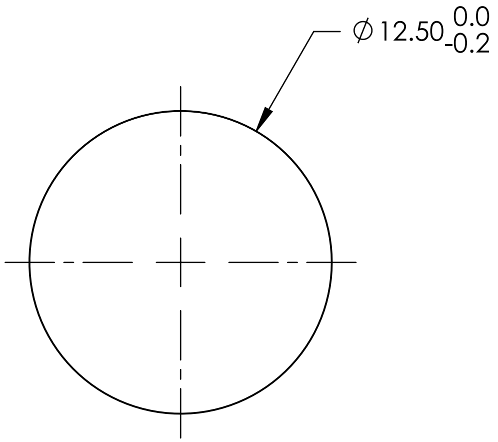
NOTES:

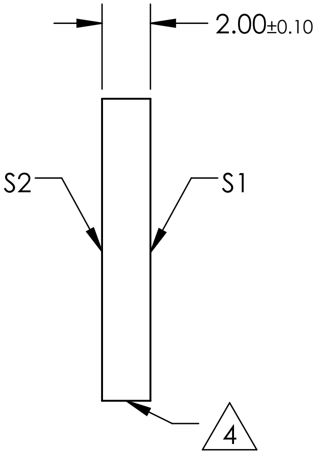
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 765 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 735nm @ 0° AOI
   T(abs): =50% FOR 750±7.5nm @ 0° AOI

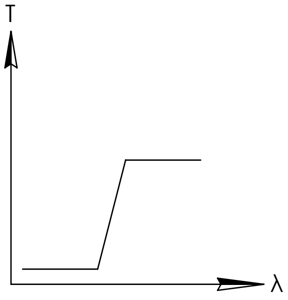
   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 750nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN mm

DWG NO 66226

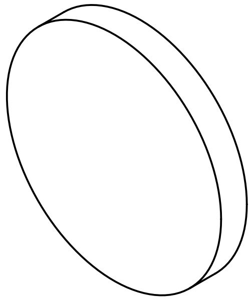
SHEET 1 OF 1

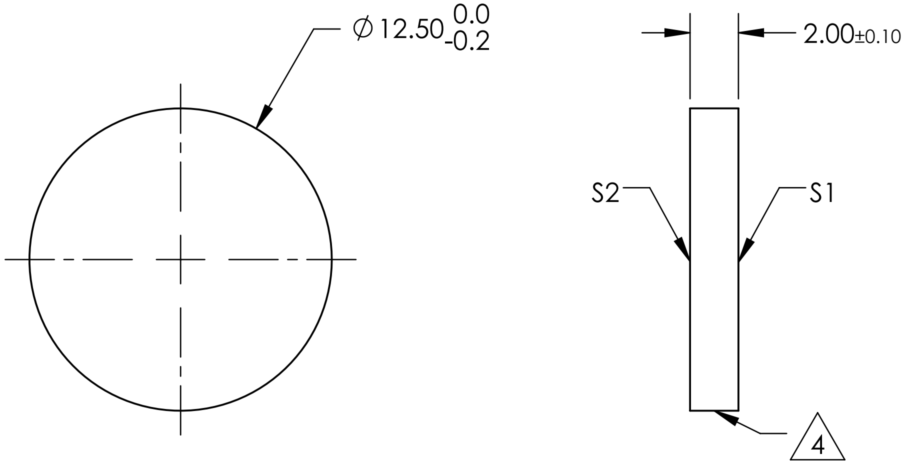
NOTES:

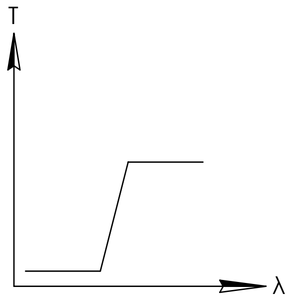
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 815 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 785nm @ 0° AOI
   T(abs): =50% FOR 800±8nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE PARTS TO THIS DRAWING







LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

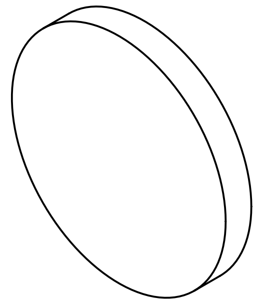
THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 800nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	66227
SHEET	1 OF 1		

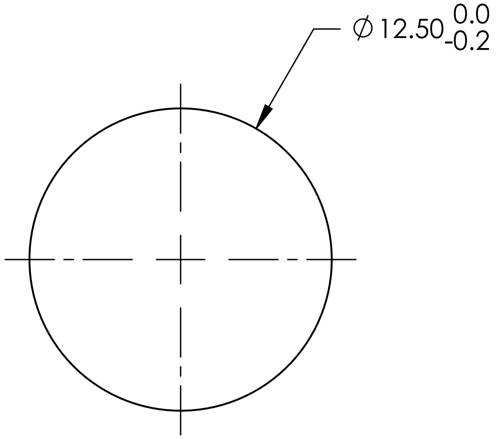
NOTES:

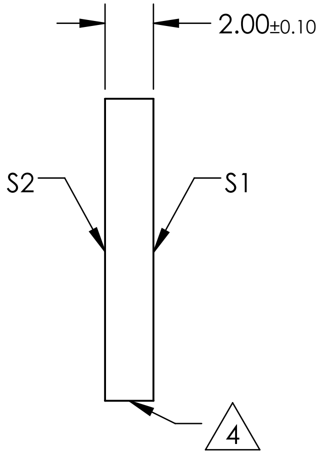
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 865 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 835nm @ 0° AOI
   T(abs): =50% FOR 850±8.5nm @ 0° AOI

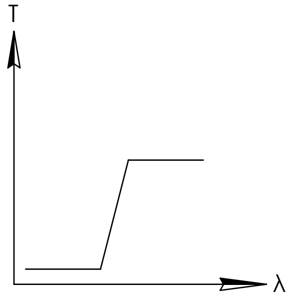
   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 850nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	66228

SHEET
1 OF 1

NOTES:

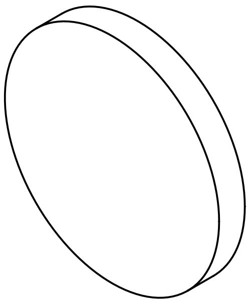
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 915 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 880nm @ 0° AOI
        T(abs): =50% FOR 900±9nm @ 0° AOI

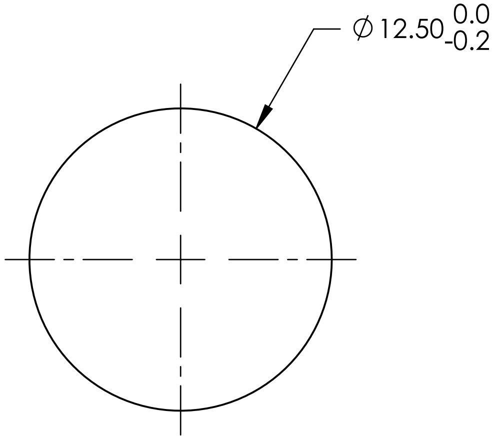
    S2:SINGLE LAYER MgF2

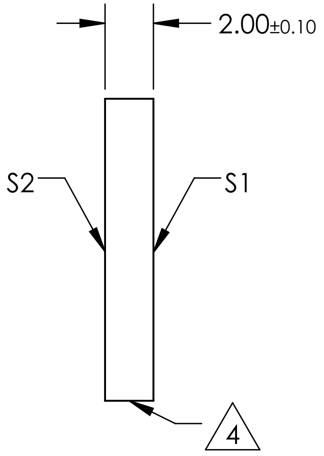
△4. FINE GRIND SURFACE

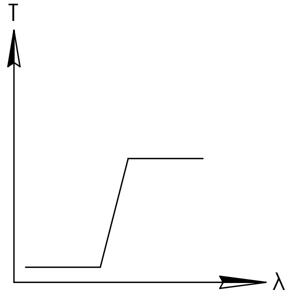
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE Ø12.5mm, 900nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN mm

DWG NO 66229

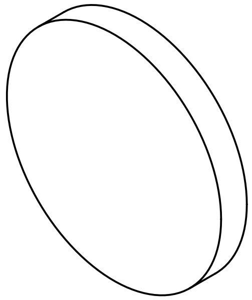
SHEET 1 OF 1

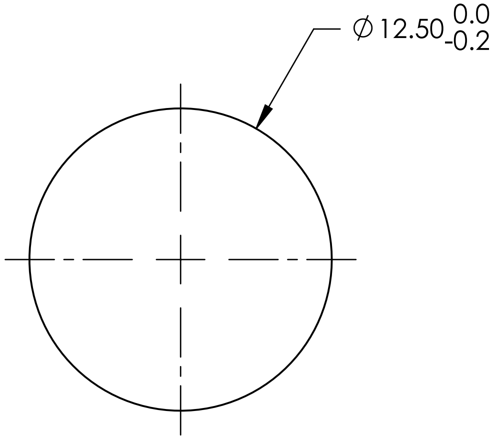
NOTES:

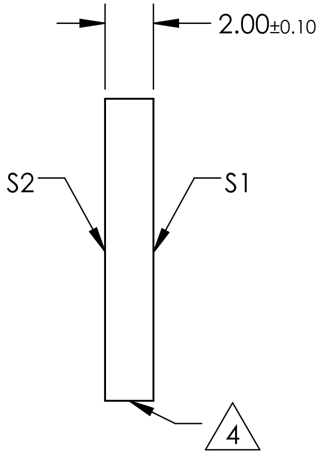
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 965 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 930nm @ 0° AOI
   T(abs): =50% FOR 950±9.5nm @ 0° AOI

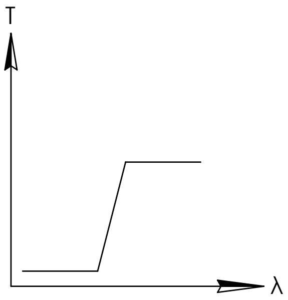
   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 950nm, HIGH PERFORMANCE LONGPASS FILTER	
ALL DIMS IN	mm	DWG NO	66230	SHEET 1 OF 1

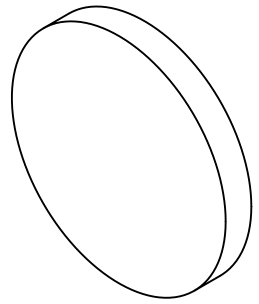
NOTES:

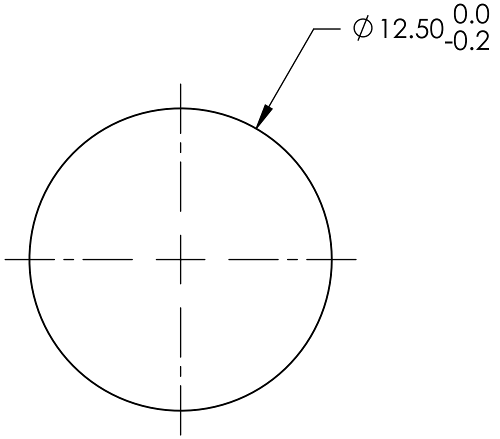
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 1020 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 980nm @ 0° AOI
        T(abs): =50% FOR 1000±10nm @ 0° AOI

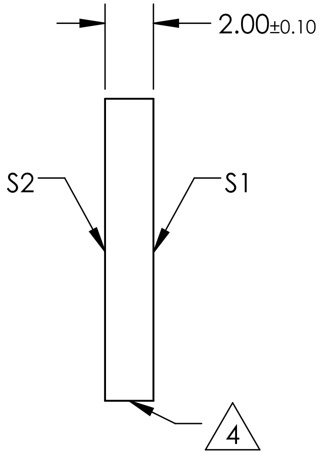
    S2:SINGLE LAYER MgF2

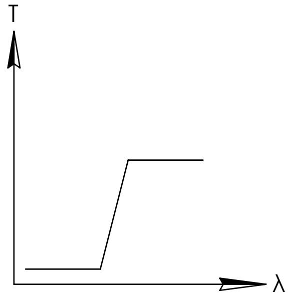
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

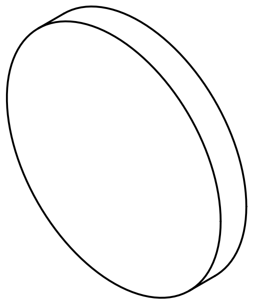
THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 1000nm, HIGH PERFORMANCE LONGPASS FILTER		
ALL DIMS IN	mm	DWG NO	66231	SHEET	1 OF 1

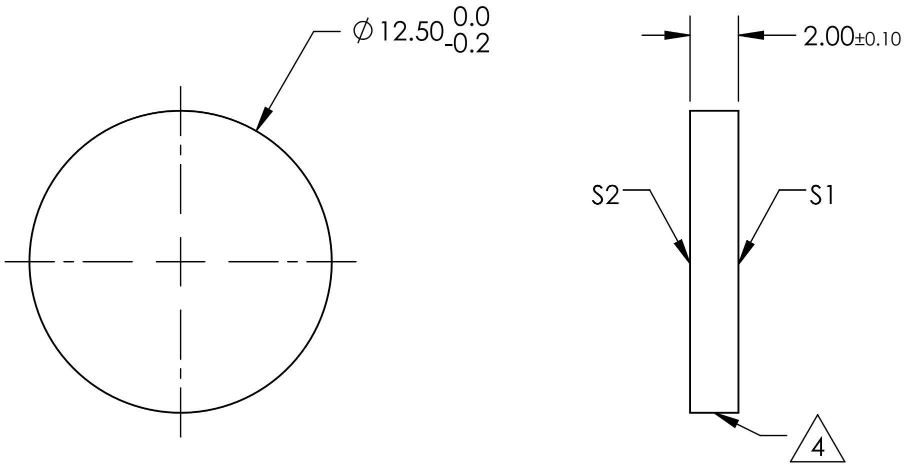
NOTES:

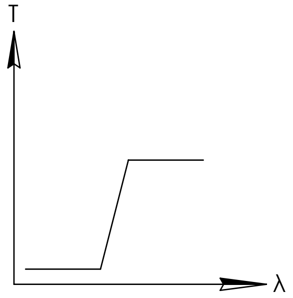
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 1070 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 1030nm @ 0° AOI
   T(abs): =50% FOR 1050±10.5nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING







LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE	Ø12.5mm, 1050nm, HIGH PERFORMANCE LONGPASS FILTER		
ALL DIMS IN	mm	DWG NO	66232

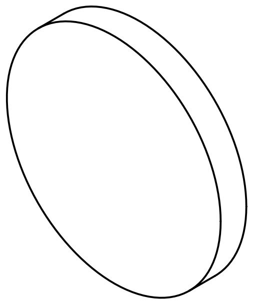
SHEET 1 OF 1

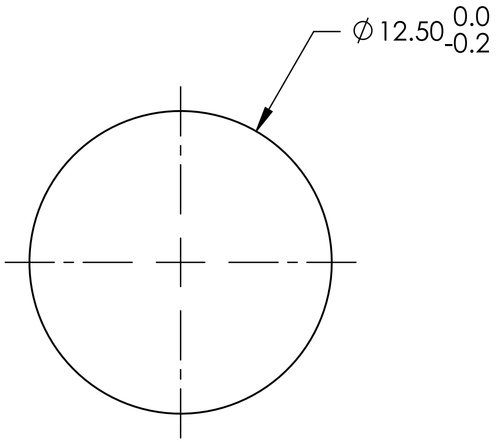
NOTES:

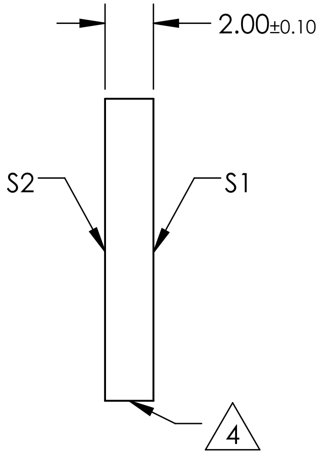
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 1120 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 1080nm @ 0° AOI
        T(abs): =50% FOR 1100±11nm @ 0° AOI

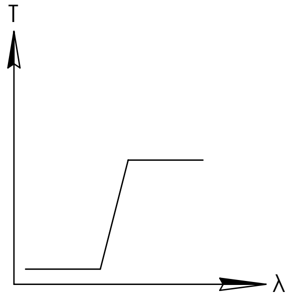
    S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING









LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 1100nm, HIGH PERFORMANCE LONGPASS FILTER	
ALL DIMS IN	mm	DWG NO	66233	SHEET 1 OF 1